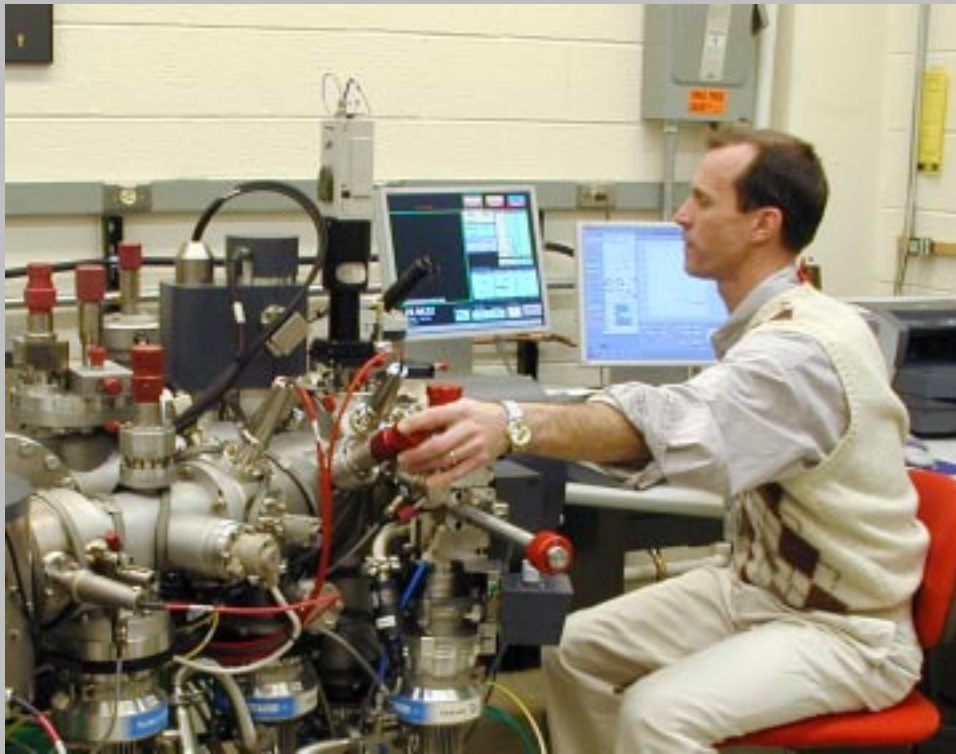


January 2004

New system tests material surfaces



ADVANCED TECHNOLOGY — Dr. Howard Smith fine-tunes the newly acquired Secondary Ion Mass Spectrometry analysis system used to identify and quantify materials in semiconductors, aircraft corrosion and oxidation samples, and thin films. Dr. Smith is a scientist with the Materials and Manufacturing Directorate. The system is capable of analyzing materials surfaces and depth composition with sensitivities as high as parts per billion. A ribbon cutting ceremony for the new system was held Dec. 12 at ML's Survivability and Sensor Materials Division. (Air Force photo by Rae Parks)